



NPN Epitaxial Planar Silicon Transistor **2SC3807**—High-hFE, Low Frequency **General-Purpose Amplifier Applications**

Applications

· Low-frequency general-purpose amplifiers, drivers.

Features

- Large current capacity (IC=2A).
- · Adoption of MBIT process.
- High DC current gain (hFE=800 to 3200).
- Low collector-to-emitter saturation voltage ($V_{CE}(sat) \le 0.5V$).
- High VEBO (VEBO \geq 15V).

Specifications

Absolute Maximum Ratings at Ta=25°C

Parameter	Symbol	Conditions	Ratings	Unit
Collector-to-Base Voltage	VCBO		30	V
Collector-to-Emitter Voltage	VCEO		25	V
Emitter-to-Base Voltage	VEBO		15	V
Collector Current	IC		2	А
Collector Current (Pulse)	ICP		4	А
Collector Dissipation	Pe		1.2	W
	PC	Tc=25°C	15	W
Junction Temperature	Tj		150	°C
Storage Temperature	Tstg		-55 to +150	°C

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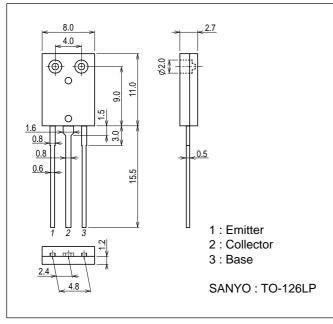
Electrical Characteristics at Ta=25°C

Parameter	Symbol	Conditions	Ratings			Linit
			min	typ	max	Unit
Collector Cutoff Current	Ісво	V _{CB} =20V, I _E =0A			0.1	μΑ
Emitter Cutoff Current	IEBO	V _{EB} =10V, I _C =0A			0.1	μΑ
DC Current Gain	hFE1	VCE=5V, IC=500mA	800	1500	3200	
	hFE2	V _{CE} =5V, I _C =1A	600			
Gain-Bandwidth Product	fT	V _{CE} =10V, I _C =50mA		260		MHz
Output Capacitance	Cob	VCB=10V, f=1MHz		27		pF
Collector-to-Emitter Saturation Voltage	V _{CE} (sat)	IC=1A, IB=20mA		0.15	0.5	V
Base-to-Emitter Saturation Voltage	V _{BE} (sat)	IC=1A, IB=20mA		0.85	1.2	V
Collector-to-Base Breakdown Voltage	V(BR)CBO	IC=10μA, IE=0A	30			V
Collector-to-Emitter Breakdown Voltage	V(BR)CEO	IC=1mA, RBE=∞	25			V
Emitter-to-Base Breakdown Voltage	V(BR)EBO	IE=10μA, IC=0A	15			V
Turn-ON Time	ton	See specified Test Circuit.		0.14		μS
Storage Time	tstg	See specified Test Circuit.		1.35		μs
Fall Time	tf	See specified Test Circuit.		0.1		μS

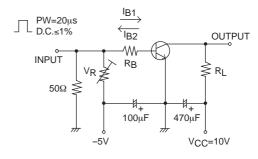
Package Dimensions

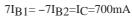
unit : mm (typ)

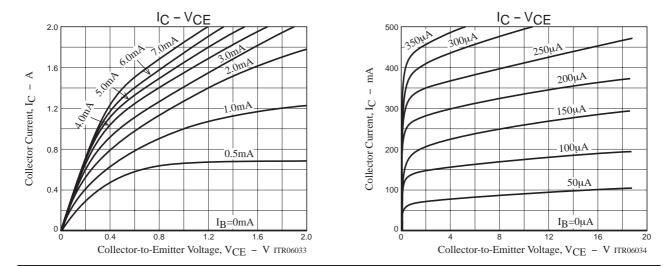
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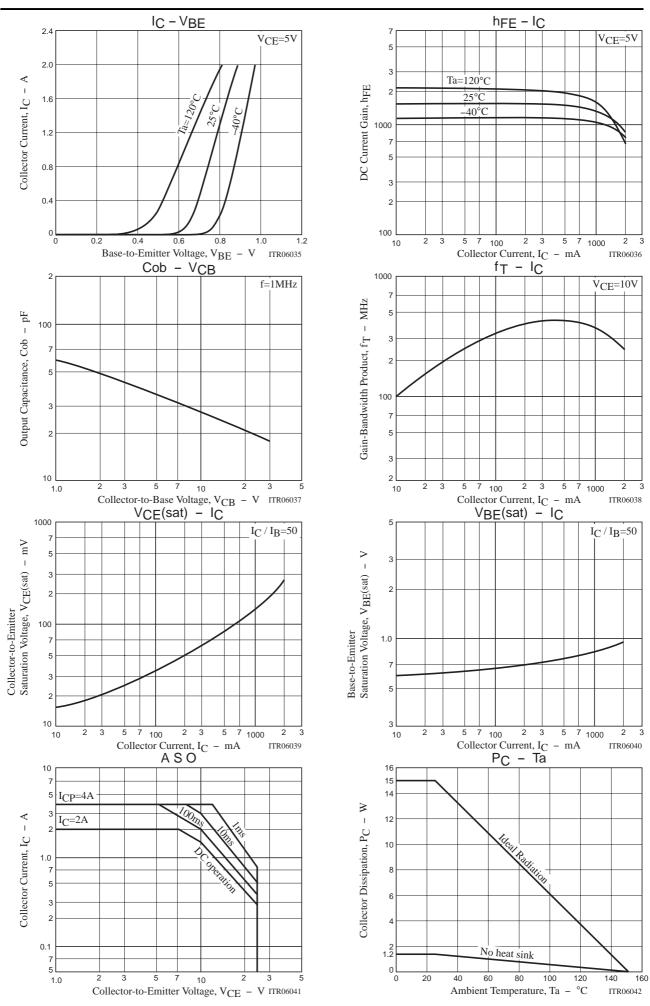


Switching Time Test Circuit









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